

DUAL 4-INPUT POSITIVE-NAND BUFFERS/LINE DRIVERS

S54S40

S54S140

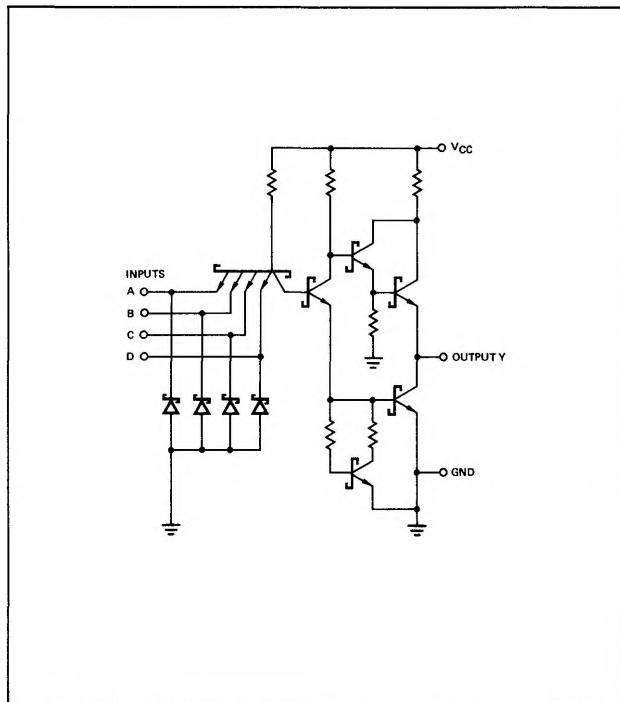
N74S40

N74S140

S54S40-A,F,W • S54S140-A,F,W • N74S40-A,F • N74S140-A,F

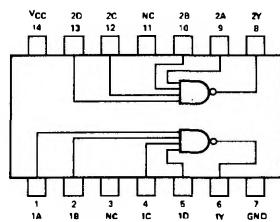
DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS

A,F PACKAGE



RECOMMENDED MAXIMUM FAN-OUT FROM EACH OUTPUT

Loads at a high logic level	60
Load at a low logic level	30

NC — No internal connection

ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
V _{IH}	High-level input voltage	2			V
V _{IL}	Low-level input voltage		0.8		V
V _I	Input clamp voltage		-1.2		V
V _{OH}	High-level output voltage	2.5	3.4		V
V _{OL}	Low-level output voltage	2.7	3.4		V
I _I	Input current at maximum input voltage	2			V
I _{IH}	High-level input current (each input)			100	μA
I _{IL}	Low-level input current (each input)			-4	mA
I _{OS}	Short-circuit output current [†]			-225	mA
I _{CCH}	Supply current, high-level output (average per gate)			5	mA
I _{CCL}	Supply current, low-level output (average per gate)			12.5	mA

NOTES:

- A. The pulse generator has the following characteristics: V_{in(1)} = 3V, V_{in(0)} = 0V, t₁ = t₀ = 2.5ns, PRR = 1 MHz, duty cycle = 50%, and Z_{out} ≈ 50Ω.
- B. Inputs not under test are at 2.7V.
- C. C_L includes probe and jig capacitance.

SIGNETICS DIGITAL 54/74 TTL SERIES - S54S40 • S54S140 • N74S40 • N74S140

SWITCHING CHARACTERISTICS, $V_{CC} = 5V$, $T_A = 25^\circ C$, $N = 30$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH} Propagation delay time, low-to-high-level output	$C_L = 50\text{pF}, R_L = 93\Omega$	2	4	6.5	ns
	$C_L = 150\text{pF}, R_L = 93\Omega$		6		ns
t_{PHL} Propagation delay time, high-to-low-level output	$C_L = 50\text{pF}, R_L = 93\Omega$	2	4	6.5	ns
	$C_L = 150\text{pF}, R_L = 93\Omega$		6		ns

* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable series on the second page of this section.

** All typical values are at $V_{CC} = 5V$, $T_A = 25^\circ C$.

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed 100 milliseconds.